Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/544,289	HIYOSHI, TAKAYUKI	
Examiner	Art Unit	

Hai C. Pham

2861

	SEARCHED			
Class	Subclass	Date	Examiner	
347	130, 236, 238, 241- 242, 256	4/13/2005	НР	
	257			

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR)
	DATE	EXMR
EAST TEXT SEARCH	4/13/2005	НР
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